

PA-IDC

QUERY CONTROL FORM			RTIS USE ONLY	
Application No.	10/660,686	Prepared by	J. Robbins	Tracking Number
Examiner-GAU	Lee-2881	Date	9-2-04	Week Date
		No. of queries	(1)	IFN RU-3

JACKET

a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION

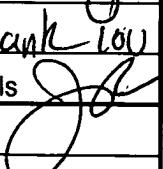
- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

MESSAGE

Please either initial or line through citations on PTO-1449 form dated 2-24-04 per toc. Copy provided for reference.

CLAIMS

- a. Claim(s) Missing
- b. Improper Dependency
- c. Duplicate Numbers
- d. Incorrect Numbering
- e. Index Disagrees
- f. Punctuation
- g. Amendments
- h. Bracketing
- i. Missing Text
- j. Duplicate Text
- k. Other

Thank You
initials 

RESPONSE

initials



Sheet 1 of 1

Form PTO-1449 IRSY. 7.801 U.S. Department of Commerce Patent and Trademark Office		ATTORNEY DOCKET NO. 5000-1-307
		SERIAL NO. 10/600,686
LIST OF DOCUMENTARY INFORMATION CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Joo-Hoon Lee et al.
		FILING DATE June 20, 2003
		GROUP Unassigned

U.S. PATENT DOCUMENTS

EXAMINE R INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
	AA	5,323,476	6/21/94	Mueller et al.	385	43	07/16/93

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO
	AB	WO02-063347A2	8/15/02	PCT	G02B		X
	AC	JP10090537	4/10/98	Japan	G02B6	122	X

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AD	"Very Low Insertion Loss Arrayed-Waveguide Grating with Vertically Tapered Waveguides;" A. Sugita et al., XP000968634; September 2000; pgs. 1180-1182.	
AE	"A Review on Fabrication Technologies for the Monolithic Integration of Tapers with III-V Semiconductor Devices;" I. Moerman et al.; XP002146284; December 1997; pgs. 1308-1320.	

EXAMINER:	DATE CONSIDERED:
"EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant."	